

Heiko MÃ¼ller

List of Publications by Year in descending order

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papers

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1163117

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14
docs citations

14
times ranked

565
citing authors

#	ARTICLE	IF	CITATIONS
1	Advancing the Hexapole Cs-Corrector for the Scanning Transmission Electron Microscope. <i>Microscopy and Microanalysis</i> , 2006, 12, 442-455.	0.4	103
2	Chromatic Aberration Correction for Atomic Resolution TEM Imaging from 20 to 80ÅkV. <i>Physical Review Letters</i> , 2016, 117, 076101.	7.8	99
3	Thermal Magnetic Field Noise Limits Resolution in Transmission Electron Microscopy. <i>Physical Review Letters</i> , 2013, 111, 046101.	7.8	97
4	Chapter 2 Present and Future Hexapole Aberration Correctors for High-Resolution Electron Microscopy. <i>Advances in Imaging and Electron Physics</i> , 2008, , 43-119.	0.2	35
5	Aplanatic imaging systems for the transmission electron microscope. <i>Nuclear Instruments and Methods in Physics Research, Section A: Accelerators, Spectrometers, Detectors and Associated Equipment</i> , 2011, 645, 20-27.	1.6	32
6	Aberration-corrected optics: from an idea to a device. <i>Physics Procedia</i> , 2008, 1, 167-178.	1.2	17
7	Test and characterization of a new post-column imaging energy filter. <i>Advances in Imaging and Electron Physics</i> , 2019, 212, 35-70.	0.2	14
8	A flexible multi-stimuli in situ (S)TEM: Concept, optical performance, and outlook. <i>Ultramicroscopy</i> , 2015, 151, 31-36.	1.9	9
9	Performance of the SALVE-microscope: Atomic-resolution TEM Imaging at 20 kV. <i>Microscopy and Microanalysis</i> , 2016, 22, 878-879.	0.4	6
10	Exploiting the full potential of the advanced two-hexapole corrector for STEM exemplified at 60kV. <i>Ultramicroscopy</i> , 2022, 233, 113440.	1.9	5
11	On Proper Phase Contrast Imaging in Aberration Corrected TEM. <i>Microscopy and Microanalysis</i> , 2014, 20, 926-927.	0.4	2
12	The Dresden in-situ (S)TEM special with a continuous-flow liquid-helium cryostat. <i>Ultramicroscopy</i> , 2019, 203, 12-20.	1.9	1
13	Advancing the Hexapole Cs-Corrector for the Transmission Electron Microscope. <i>Microscopy and Microanalysis</i> , 2020, 26, 2150-2151.	0.4	1